

<b>Notice of References Cited</b>	Application/Control No. 10/716,780		Applicant(s)/Patent Under Reexamination PARK, BYUNG-JUN	
	Examiner Thinh T Nguyen		Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,372,571	04-2002	Kim, Jae Kap	438/239
*	B	US-6,365,453	04-2002	Deboer et al.	438/253
*	C	US-6,448,140	09-2002	Liaw, Jhon-Jhy	438/279
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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